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Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	2006
Number of Logic Elements/Cells	20060
Total RAM Bits	294912
Number of I/O	233
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	324-BGA
Supplier Device Package	324-FBGA (19x19)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1c20f324c8

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Logic Array Blocks

Each LAB consists of 10 LEs, LE carry chains, LAB control signals, a local interconnect, look-up table (LUT) chain, and register chain connection lines. The local interconnect transfers signals between LEs in the same LAB. LUT chain connections transfer the output of one LE's LUT to the adjacent LE for fast sequential LUT connections within the same LAB. Register chain connections transfer the output of one LE's register to the adjacent LE's register within a LAB. The Quartus® II Compiler places associated logic within a LAB or adjacent LABs, allowing the use of local, LUT chain, and register chain connections for performance and area efficiency. Figure 2–2 details the Cyclone LAB.

Row Interconnect Column Interconnect Direct link interconnect from Direct link adjacent block interconnect from adjacent block Direct link Direct link interconnect to interconnect to adjacent block adjacent block LÄB Local Interconnect

Figure 2-2. Cyclone LAB Structure

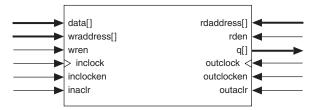
LAB Interconnects

The LAB local interconnect can drive LEs within the same LAB. The LAB local interconnect is driven by column and row interconnects and LE outputs within the same LAB. Neighboring LABs, PLLs, and M4K RAM blocks from the left and right can also drive a LAB's local interconnect through the direct link connection. The direct link connection feature minimizes the use of row and column interconnects, providing higher

In addition to true dual-port memory, the M4K memory blocks support simple dual-port and single-port RAM. Simple dual-port memory supports a simultaneous read and write. Single-port memory supports non-simultaneous reads and writes. Figure 2–13 shows these different M4K RAM memory port configurations.

Figure 2–13. Simple Dual-Port and Single-Port Memory Configurations

Simple Dual-Port Memory



Single-Port Memory (1)



Note to Figure 2–13:

 Two single-port memory blocks can be implemented in a single M4K block as long as each of the two independent block sizes is equal to or less than half of the M4K block size.

The memory blocks also enable mixed-width data ports for reading and writing to the RAM ports in dual-port RAM configuration. For example, the memory block can be written in $\times 1$ mode at port A and read out in $\times 16$ mode from port B.

The Cyclone memory architecture can implement fully synchronous RAM by registering both the input and output signals to the M4K RAM block. All M4K memory block inputs are registered, providing synchronous write cycles. In synchronous operation, the memory block generates its own self-timed strobe write enable (wren) signal derived from a global clock. In contrast, a circuit using asynchronous RAM must generate the RAM wren signal while ensuring its data and address signals meet setup and hold time specifications relative to the wren

Independent Clock Mode

The M4K memory blocks implement independent clock mode for true dual-port memory. In this mode, a separate clock is available for each port (ports A and B). Clock A controls all registers on the port A side, while clock B controls all registers on the port B side. Each port, A and B, also supports independent clock enables and asynchronous clear signals for port A and B registers. Figure 2–17 shows an M4K memory block in independent clock mode.

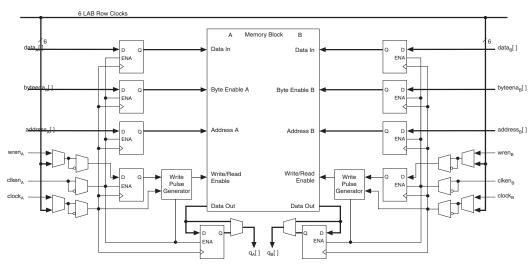


Figure 2–17. Independent Clock Mode Notes (1), (2)

Notes to Figure 2–17:

- (1) All registers shown have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

Input/Output Clock Mode

Input/output clock mode can be implemented for both the true and simple dual-port memory modes. On each of the two ports, A or B, one clock controls all registers for inputs into the memory block: data input, wren, and address. The other clock controls the block's data output registers. Each memory block port, A or B, also supports independent clock enables and asynchronous clear signals for input and output registers. Figures 2–18 and 2–19 show the memory block in input/output clock mode.

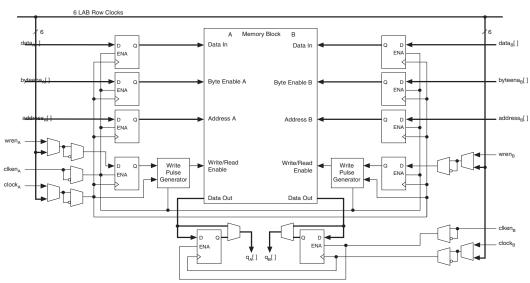


Figure 2–18. Input/Output Clock Mode in True Dual-Port Mode Notes (1), (2)

Notes to Figure 2–18:

- (1) All registers shown have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

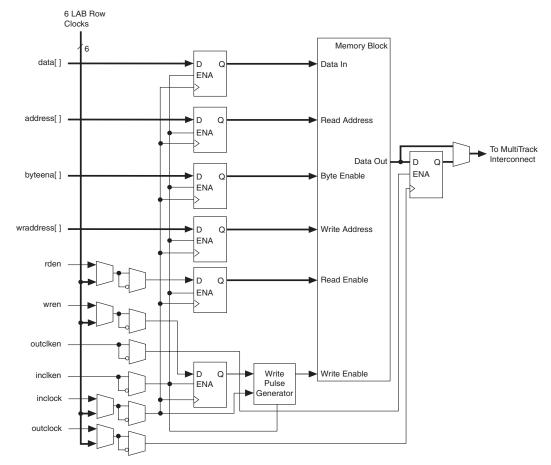


Figure 2–19. Input/Output Clock Mode in Simple Dual-Port Mode Notes (1), (2)

Notes to Figure 2-19:

- (1) All registers shown except the rden register have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

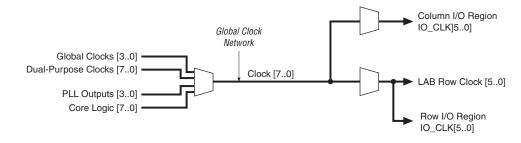
Dual-Purpose Clock Pins

Each Cyclone device except the EP1C3 device has eight dual-purpose clock pins, DPCLK[7..0] (two on each I/O bank). EP1C3 devices have five DPCLK pins in the 100-pin TQFP package. These dual-purpose pins can connect to the global clock network (see Figure 2–22) for high-fanout control signals such as clocks, asynchronous clears, presets, and clock enables, or protocol control signals such as TRDY and IRDY for PCI, or DQS signals for external memory interfaces.

Combined Resources

Each Cyclone device contains eight distinct dedicated clocking resources. The device uses multiplexers with these clocks to form six-bit buses to drive LAB row clocks, column IOE clocks, or row IOE clocks. See Figure 2–23. Another multiplexer at the LAB level selects two of the six LAB row clocks to feed the LE registers within the LAB.

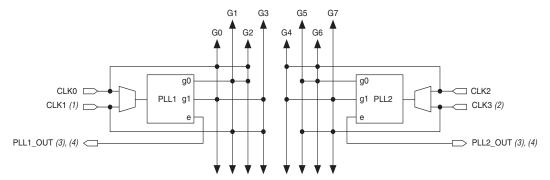
Figure 2-23. Global Clock Network Multiplexers



IOE clocks have row and column block regions. Six of the eight global clock resources feed to these row and column regions. Figure 2–24 shows the I/O clock regions.

Figure 2–26 shows the PLL global clock connections.

Figure 2-26. Cyclone PLL Global Clock Connections



Notes to Figure 2-26:

- (1) PLL 1 supports one single-ended or LVDS input via pins CLKO and CLK1.
- (2) PLL2 supports one single-ended or LVDS input via pins CLK2 and CLK3.
- (3) PLL1_OUT and PLL2_OUT support single-ended or LVDS output. If external output is not required, these pins are available as regular user I/O pins.
- (4) The EP1C3 device in the 100-pin TQFP package does not support external clock output. The EP1C6 device in the 144-pin TQFP package does not support external clock output from PLL2.

Table 2–7 shows the global clock network sources available in Cyclone devices.

Table 2-7. GI	Table 2–7. Global Clock Network Sources (Part 1 of 2)										
Sou	rce	GCLKO	GCLK1	GCLK2	GCLK3	GCLK4	GCLK5	GCLK6	GCLK7		
PLL Counter	PLL1 G0	_	✓	✓	_	_	_	_	_		
Output	PLL1 G1	✓	_	_	✓	_	_	_	_		
	PLL2 G0 (1)	_	_	_	_	_	✓	✓	_		
	PLL2 G1 (1)	_	_	_	_	✓	_	_	✓		
Dedicated	CLK0	✓	_	✓	_	_	_	_	_		
Clock Input Pins	CLK1 (2)	_	✓	_	✓	_	_	_	_		
	CLK2	_	_	_	_	✓	_	✓	_		
	CLK3 (2)	_	_	_	_	_	✓	_	✓		

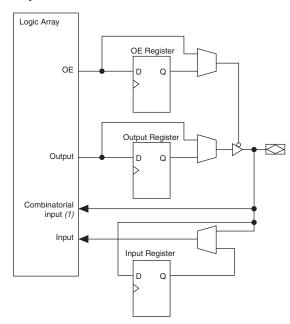


Figure 2-27. Cyclone IOE Structure

Note to Figure 2-27:

 There are two paths available for combinatorial inputs to the logic array. Each path contains a unique programmable delay chain.

The IOEs are located in I/O blocks around the periphery of the Cyclone device. There are up to three IOEs per row I/O block and up to three IOEs per column I/O block (column I/O blocks span two columns). The row I/O blocks drive row, column, or direct link interconnects. The column I/O blocks drive column interconnects. Figure 2–28 shows how a row I/O block connects to the logic array. Figure 2–29 shows how a column I/O block connects to the logic array.

to automatically minimize setup time while providing a zero hold time. Programmable delays can increase the register-to-pin delays for output registers. Table 2–9 shows the programmable delays for Cyclone devices.

Table 2–9. Cyclone Programmable Delay Chain					
Programmable Delays Quartus II Logic Option					
Input pin to logic array delay	Decrease input delay to internal cells				
Input pin to input register delay	Decrease input delay to input registers				
Output pin delay	Increase delay to output pin				

There are two paths in the IOE for a combinatorial input to reach the logic array. Each of the two paths can have a different delay. This allows you adjust delays from the pin to internal LE registers that reside in two different areas of the device. The designer sets the two combinatorial input delays by selecting different delays for two different paths under the **Decrease input delay to internal cells** logic option in the Quartus II software. When the input signal requires two different delays for the combinatorial input, the input register in the IOE is no longer available.

The IOE registers in Cyclone devices share the same source for clear or preset. The designer can program preset or clear for each individual IOE. The designer can also program the registers to power up high or low after configuration is complete. If programmed to power up low, an asynchronous clear can control the registers. If programmed to power up high, an asynchronous preset can control the registers. This feature prevents the inadvertent activation of another device's active-low input upon power up. If one register in an IOE uses a preset or clear signal then all registers in the IOE must use that same signal if they require preset or clear. Additionally a synchronous reset signal is available to the designer for the IOE registers.

External RAM Interfacing

Cyclone devices support DDR SDRAM and FCRAM interfaces at up to 133 MHz through dedicated circuitry.

DDR SDRAM and FCRAM

Cyclone devices have dedicated circuitry for interfacing with DDR SDRAM. All I/O banks support DDR SDRAM and FCRAM I/O pins. However, the configuration input pins in bank 1 must operate at 2.5 V because the SSTL-2 $\rm V_{CCIO}$ level is 2.5 V. Additionally, the configuration

Advanced I/O Standard Support

Cyclone device IOEs support the following I/O standards:

- 3.3-V LVTTL/LVCMOS
- 2.5-V LVTTL/LVCMOS
- 1.8-V LVTTL/LVCMOS
- 1.5-V LVCMOS
- 3.3-V PCI
- LVDS
- RSDS
- SSTL-2 class I and II
- SSTL-3 class I and II
- Differential SSTL-2 class II (on output clocks only)

Table 2–12 describes the I/O standards supported by Cyclone devices.

Table 2–12. Cyclone I/C) Standards			
I/O Standard	Туре	Input Reference Voltage (V _{REF}) (V)	Output Supply Voltage (V _{CCIO}) (V)	Board Termination Voltage (V _{TT}) (V)
3.3-V LVTTL/LVCMOS	Single-ended	N/A	3.3	N/A
2.5-V LVTTL/LVCMOS	Single-ended	N/A	2.5	N/A
1.8-V LVTTL/LVCMOS	Single-ended	N/A	1.8	N/A
1.5-V LVCMOS	Single-ended	N/A	1.5	N/A
3.3-V PCI (1)	Single-ended	N/A	3.3	N/A
LVDS (2)	Differential	N/A	2.5	N/A
RSDS (2)	Differential	N/A	2.5	N/A
SSTL-2 class I and II	Voltage-referenced	1.25	2.5	1.25
SSTL-3 class I and II	Voltage-referenced	1.5	3.3	1.5
Differential SSTL-2 (3)	Differential	1.25	2.5	1.25

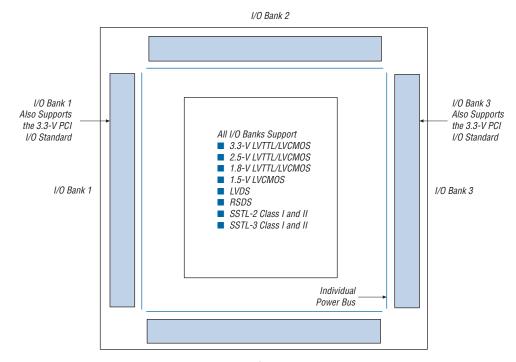
Notes to Table 2-12:

- (1) There is no megafunction support for EP1C3 devices for the PCI compiler. However, EP1C3 devices support PCI by using the LVTTL 16-mA I/O standard and drive strength assignments in the Quartus II software. The device requires an external diode for PCI compliance.
- (2) EP1C3 devices in the 100-pin TQFP package do not support the LVDS and RSDS I/O standards.
- (3) This I/O standard is only available on output clock pins (PLL_OUT pins). EP1C3 devices in the 100-pin package do not support this I/O standard as it does not have PLL_OUT pins.

Cyclone devices contain four I/O banks, as shown in Figure 2–35. I/O banks 1 and 3 support all the I/O standards listed in Table 2–12. I/O banks 2 and 4 support all the I/O standards listed in Table 2–12 except the 3.3-V PCI standard. I/O banks 2 and 4 contain dual-purpose DQS, DQ,

and DM pins to support a DDR SDRAM or FCRAM interface. I/O bank 1 can also support a DDR SDRAM or FCRAM interface, however, the configuration input pins in I/O bank 1 must operate at 2.5 V. I/O bank 3 can also support a DDR SDRAM or FCRAM interface, however, all the JTAG pins in I/O bank 3 must operate at 2.5 V.

Figure 2–35. Cyclone I/O Banks Notes (1), (2)



I/O Bank 4

Notes to Figure 2–35:

- (1) Figure 2–35 is a top view of the silicon die.
- (2) Figure 2–35 is a graphic representation only. Refer to the pin list and the Quartus II software for exact pin locations.

Each I/O bank has its own VCCIO pins. A single device can support 1.5-V, 1.8-V, 2.5-V, and 3.3-V interfaces; each individual bank can support a different standard with different I/O voltages. Each bank also has dual-purpose VREF pins to support any one of the voltage-referenced standards (e.g., SSTL-3) independently. If an I/O bank does not use voltage-referenced standards, the $V_{\rm REF}$ pins are available as user I/O pins.

Table 4-2. C	Table 4–2. Cyclone Device Recommended Operating Conditions (Part 2 of 2)									
Symbol	Parameter	Conditions	Minimum	Maximum	Unit					
Vo	Output voltage		0	V _{CCIO}	V					
T _J	Operating junction temperature	For commercial use	0	85	° C					
		For industrial use	-40	100	° C					
		For extended- temperature use	-40	125	° C					

Table 4-	3. Cyclone Device DC Operating	Conditions Note (6)				
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
I _I	Input pin leakage current	$V_I = V_{CCIOmax}$ to 0 V (8)	-10	_	10	μΑ
I _{OZ}	Tri-stated I/O pin leakage current	$V_O = V_{CCIOmax}$ to 0 V (8)	-10	_	10	μА
I _{CC0}	V _{CC} supply current (standby)	EP1C3	_	4	_	mA
	(All M4K blocks in power-down mode) (7)	EP1C4	_	6	_	mA
		EP1C6	_	6	_	mA
		EP1C12	_	8	_	mA
		EP1C20	_	12	_	mA
R _{CONF} (9)		$V_{I} = 0 \text{ V}; V_{CCI0} = 3.3 \text{ V}$	15	25	50	kΩ
	before and during configuration	$V_{I} = 0 \text{ V}; V_{CCI0} = 2.5 \text{ V}$	20	45	70	kΩ
		$V_I = 0 \ V; \ V_{CCI0} = 1.8 \ V$	30	65	100	kΩ
		$V_I = 0 \ V; \ V_{CCI0} = 1.5 \ V$	50	100	150	kΩ
	Recommended value of I/O pin external pull-down resistor before and during configuration	_	_	1	2	kΩ

Table 4-4.	Table 4–4. LVTTL Specifications									
Symbol	Parameter	Conditions	Minimum	Maximum	Unit					
V _{CCIO}	Output supply voltage	_	3.0	3.6	V					
V _{IH}	High-level input voltage	_	1.7	4.1	V					
V _{IL}	Low-level input voltage	_	-0.5	0.7	V					
V _{OH}	High-level output voltage	$I_{OH} = -4 \text{ to } -24 \text{ mA } (11)$	2.4	_	V					
V _{OL}	Low-level output voltage	I _{OL} = 4 to 24 mA (11)	_	0.45	V					

Performance

The maximum internal logic array clock tree frequency is limited to the specifications shown in Table 4–19.

Table 4–19.	Table 4–19. Clock Tree Maximum Performance Specification										
Parameter	Definition	-6 S	peed G	rade	-7 S	peed G	rade	-8 S	peed G	rade	Units
	Deminion	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	UIIIIS
Clock tree f _{MAX}	Maximum frequency that the clock tree can support for clocking registered logic		_	405	_	_	320		_	275	MHz

Table 4–20 shows the Cyclone device performance for some common designs. All performance values were obtained with the Quartus II software compilation of library of parameterized modules (LPM) functions or megafunctions. These performance values are based on EP1C6 devices in 144-pin TQFP packages.

Table 4-20	Table 4–20. Cyclone Device Performance									
			R	esources U	sed	Performance				
Resource Used	Design Size and Function	Mode	LEs	M4K Memory Bits	M4K Memory Blocks	-6 Speed Grade (MHz)	-7 Speed Grade (MHz)	-8 Speed Grade (MHz)		
LE	16-to-1 multiplexer	_	21	_	_	405.00	320.00	275.00		
	32-to-1 multiplexer	_	44	_	_	317.36	284.98	260.15		
	16-bit counter	_	16	_	_	405.00	320.00	275.00		
	64-bit counter (1)	_	66	_	_	208.99	181.98	160.75		

			R	esources U	sed	Performance		
Resource Used	Design Size and Function	Mode	LEs	M4K Memory Bits	M4K Memory Blocks	-6 Speed Grade (MHz)	-7 Speed Grade (MHz)	-8 Speed Grade (MHz)
M4K	RAM 128 × 36 bit	Single port	_	4,608	1	256.00	222.67	197.01
memory block	RAM 128 × 36 bit	Simple dual-port mode	_	4,608	1	255.95	222.67	196.97
	RAM 256 × 18 bit	True dual- port mode	_	4,608	1	255.95	222.67	196.97
	FIFO 128 × 36 bit	_	40	4,608	1	256.02	222.67	197.01
	Shift register 9 × 4 × 128	Shift register	11	4,536	1	255.95	222.67	196.97

Note to Table 4-20:

Internal Timing Parameters

Internal timing parameters are specified on a speed grade basis independent of device density. Tables 4–21 through 4–24 describe the Cyclone device internal timing microparameters for LEs, IOEs, M4K memory structures, and MultiTrack interconnects.

Table 4–21. LE Internal Timing Microparameter Descriptions					
Symbol	Parameter				
t _{SU}	LE register setup time before clock				
t _H	LE register hold time after clock				
t _{CO}	LE register clock-to-output delay				
t _{LUT}	LE combinatorial LUT delay for data-in to data-out				
t _{CLR}	Minimum clear pulse width				
t _{PRE}	Minimum preset pulse width				
t _{CLKHL}	Minimum clock high or low time				

⁽¹⁾ The performance numbers for this function are from an EP1C6 device in a 240-pin PQFP package.

Tables 4–32 through 4–33 show the external timing parameters on column and row pins for EP1C4 devices.

Table 4–32. EP1C4 Column Pin Global Clock External I/O Timing Parameters Note (1)

Symbol	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee	Unit	
Symbol	Min	Max	Max Min		Min	Max	UIIIL
t _{INSU}	2.471	_	2.841	_	3.210	_	ns
t _{INH}	0.000	_	0.000	_	0.000	_	ns
toutco	2.000	3.937	2.000	4.526	2.000	5.119	ns
t _{INSUPLL}	1.471	_	1.690	_	1.910	_	ns
t _{INHPLL}	0.000	_	0.000	_	0.000	_	ns
toutcople	0.500	2.080	0.500	2.392	0.500	2.705	ns

Table 4–33. EP1C4 Row Pin Global Clock External I/O Timing Parameters Note (1)

Cumbal	-6 Spee	-6 Speed Grade		-7 Speed Grade		-8 Speed Grade	
Symbol	Min	Max	Min	Max	Min	Max	Unit
t _{INSU}	2.600	_	2.990	_	3.379	_	ns
t _{INH}	0.000	_	0.000	_	0.000	_	ns
t _{outco}	2.000	3.991	2.000	4.388	2.000	5.189	ns
t _{INSUPLL}	1.300	_	1.494	_	1.689	_	ns
t _{INHPLL}	0.000	_	0.000	_	0.000	_	ns
toutcople	0.500	2.234	0.500	2.569	0.500	2.905	ns

Note to Tables 4–32 and 4–33:

⁽¹⁾ Contact Altera Applications for EP1C4 device timing parameters.

Table 4–44. Cyclone I/O Standard Output Delay Adders for Slow Slew Rate on Column Pins (Part 2 of 2)									
I/O Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		11	
i/U Star	iuaru	Min	Max	Min	Max	Min	Max	Unit	
1.5-V LVTTL	2 mA	_	6,789	_	7,807	_	8,825	ps	
	4 mA	_	5,109	_	5,875	_	6,641	ps	
	8 mA	_	4,793	_	5,511	_	6,230	ps	
SSTL-3 class I		_	1,390	_	1,598	_	1,807	ps	
SSTL-3 class I	I	_	989	_	1,137	_	1,285	ps	
SSTL-2 class I		_	1,965	_	2,259	_	2,554	ps	
SSTL-2 class I	I	_	1,692	_	1,945		2,199	ps	
LVDS	·	_	802	_	922	_	1,042	ps	

		-6 Snor	ad Grado	-7 Sno	ad Grada	-8 Sno	ad Grado	
I/O Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
,		Min	Max	Min	Max	Min	Max	
LVCMOS	2 mA	_	1,800	_	2,070	_	2,340	ps
	4 mA	_	1,311	_	1,507	_	1,704	ps
	8 mA	_	945	_	1,086	_	1,228	ps
	12 mA	_	807	_	928	_	1,049	ps
3.3-V LVTTL	4 mA	_	1,831	_	2,105	_	2,380	ps
	8 mA	_	1,484	_	1,705	_	1,928	ps
	12 mA	_	973	_	1,118	_	1,264	ps
	16 mA	_	1,012	_	1,163	_	1,315	ps
	24 mA	_	838	_	963	_	1,089	ps
2.5-V LVTTL	2 mA	_	2,747	_	3,158	_	3,570	ps
	8 mA	_	1,757	_	2,019	_	2,283	ps
	12 mA	_	1,763	_	2,026	_	2,291	ps
	16 mA	_	1,623	_	1,865	_	2,109	ps
1.8-V LVTTL	2 mA	_	5,506	_	6,331	_	7,157	ps
	8 mA	_	4,220	_	4,852	_	5,485	ps
	12 mA	_	4,008	_	4,608	_	5,209	ps
1.5-V LVTTL	2 mA	_	6,789	_	7,807	_	8,825	ps
	4 mA	_	5,109	_	5,875	_	6,641	ps
	8 mA	_	4,793	_	5,511	_	6,230	ps
3.3-V PCI		_	923	_	1,061	_	1,199	ps

Table 4–47. Cyclone IOE Programmable Delays on Row Pins								
Davamatav	Catting	-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		1114
Parameter	Setting	Min	Max	Min	Max	Min	Max	Unit
Decrease input delay to	Off	_	154	_	177	_	200	ps
internal cells	Small	_	2,212	_	2,543	_	2,875	ps
	Medium	_	2,639	_	3,034	_	3,430	ps
	Large	_	3,057	_	3,515	_	3,974	ps
	On	_	154	_	177	_	200	ps
Decrease input delay to input	Off	_	0	_	0	_	0	ps
register	On	_	3,057	_	3,515	_	3,974	ps
Increase delay to output pin	Off	_	0	_	0		0	ps
	On	_	556	_	639	_	722	ps

Note to Table 4-47:

Maximum Input and Output Clock Rates

Tables 4--48 and 4--49 show the maximum input clock rate for column and row pins in Cyclone devices.

Table 4–48. Cyclone Maximum Input Clock Rate for Column Pins						
I/O Standard	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit		
LVTTL	464	428	387	MHz		
2.5 V	392	302	207	MHz		
1.8 V	387	311	252	MHz		
1.5 V	387	320	243	MHz		
LVCMOS	405	374	333	MHz		
SSTL-3 class I	405	356	293	MHz		
SSTL-3 class II	414	365	302	MHz		
SSTL-2 class I	464	428	396	MHz		
SSTL-2 class II	473	432	396	MHz		
LVDS	567	549	531	MHz		

⁽¹⁾ EPC1C3 devices do not support the PCI I/O standard.

Table 4–49. Cyclone Maximum Input Clock Rate for Row Pins						
I/O Standard	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit		
LVTTL	464	428	387	MHz		
2.5 V	392	302	207	MHz		
1.8 V	387	311	252	MHz		
1.5 V	387	320	243	MHz		
LVCMOS	405	374	333	MHz		
SSTL-3 class I	405	356	293	MHz		
SSTL-3 class II	414	365	302	MHz		
SSTL-2 class I	464	428	396	MHz		
SSTL-2 class II	473	432	396	MHz		
3.3-V PCI (1)	464	428	387	MHz		
LVDS	567	549	531	MHz		

Note to Tables 4–48 through 4–49:

Tables 4–50 and 4–51 show the maximum output clock rate for column and row pins in Cyclone devices.

Table 4–50. Cyclone Maximum Output Clock Rate for Column Pins						
I/O Standard	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit		
LVTTL	304	304	304	MHz		
2.5 V	220	220	220	MHz		
1.8 V	213	213	213	MHz		
1.5 V	166	166	166	MHz		
LVCMOS	304	304	304	MHz		
SSTL-3 class I	100	100	100	MHz		
SSTL-3 class II	100	100	100	MHz		
SSTL-2 class I	134	134	134	MHz		
SSTL-2 class II	134	134	134	MHz		
LVDS	320	320	275	MHz		

Note to Table 4-50:

(1) EP1C3 devices do not support the PCI I/O standard.

⁽¹⁾ EP1C3 devices do not support the PCI I/O standard. These parameters are only available on row I/O pins.

Table 4–52. Cyclone PLL Specifications (Part 2 of 2)							
Symbol	Parameter	Min	Max	Unit			
f _{OUT} (to global clock)	PLL output frequency (-6 speed grade)	15.625	405	MHz			
	PLL output frequency (-7 speed grade)	15.625	320	MHz			
	PLL output frequency (-8 speed grade)	15.625	275	MHz			
t _{OUT} DUTY	Duty cycle for external clock output (when set to 50%)	45.00	55	%			
t _{JITTER} (1)	Period jitter for external clock output	_	±300 (2)	ps			
t _{LOCK} (3)	Time required to lock from end of device configuration	10.00	100	μs			
f _{vco}	PLL internal VCO operating range	500.00	1,000	MHz			
-	Minimum areset time	10	_	ns			
N, G0, G1, E	Counter values	1	32	integer			

Notes to Table 4-52:

- (1) The t_{JITTER} specification for the PLL[2..1]_OUT pins are dependent on the I/O pins in its V_{CCIO} bank, how many of them are switching outputs, how much they toggle, and whether or not they use programmable current strength or slow slew rate.
- (2) $f_{OUT} \ge 100$ MHz. When the PLL external clock output frequency (f_{OUT}) is smaller than 100 MHz, the jitter specification is 60 mUI.
- (3) $f_{IN/N}$ must be greater than 200 MHz to ensure correct lock detect circuit operation below -20 C. Otherwise, the PLL operates with the specified parameters under the specified conditions.

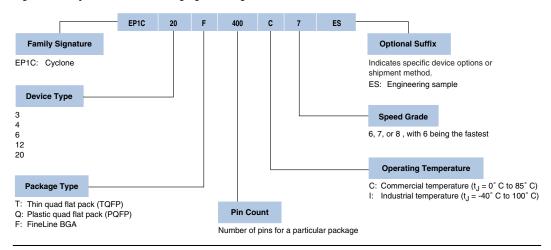


Figure 5-1. Cyclone Device Packaging Ordering Information

Referenced Documents

This chapter references the following documents:

- Package Information for Cyclone Devices chapter in the Cyclone Device Handbook
- Quartus II Handbook

Document Revision History

Table 5–1 shows the revision history for this chapter.

Table 5–1. Document Revision History						
Date and Document Version	Changes Made	Summary of Changes				
May 2008 v1.4	Minor textual and style changes. Added "Referenced Documents" section.	_				
January 2007 v1.3	Added document revision history.	_				
August 2005 v1.2	Minor updates.	_				